

Notice of References Cited	Application/Control No. 10/708,154	Applicant(s)/Patent Under Reexamination FU ET AL.	
	Examiner CHIA-WEI A. CHEN	Art Unit 2622	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,101,339	08-2000	Miki et al.	396/301
*	B	US-6,295,413	09-2001	Ogasawara, Akira	396/155
*	C	US-6,424,843	07-2002	Reitmaa et al.	455/566
	D	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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